

<b>Notice of References Cited</b>	Application/Control No. 10/608,719	Applicant(s)/Patent Under Reexamination LEE ET AL.	
	Examiner VanThu Nguyen	Art Unit 2824	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0198098 A1	10-2003	Fujioka et al.	365/200
*	B	US-6,603,704 B2	08-2003	Wilson, Alan J.	365/230.08
*	C	US-6,392,958 B1	05-2002	Lee, Sun Hyoung	365/233.5
*	D	US-5,588,130 A	12-1996	Fujishima et al.	711/118
*	E	US-RE35,921	10-1998	Harlin et al.	365/233
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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